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FOR IMMEDIATE RELEASE

IN-LINE CIS, CIGS, CIGSSe AND CdTe PV PANEL FILM COMPOSITION ANALYSIS AND THICKNESS MEASUREMENT

HOLBROOK, NY - **Solar Metrology**, a global provider of X-Ray Fluorescence (XRF) analysis tools, expands its portfolio of System SMX thin film composition and thickness measurement tools with the introduction of model **SMX-ILH**.

SMX-ILH is designed for in-line composition and thickness control of CIS, CIGS, CIGSSe and CdTe photovoltaic thin film depositions. It offers a full (600 x 1200 mm) lateral range of measurement and can be inserted into printed, electrochemical and thermal film deposition processes.

SMX-ILH provides process control for active, contact and TCO layers in PV thin film stacks and is capable of analyzing rigid glass, flexible stainless steel and polyimide roll-to-roll substrates. A proprietary thermal shield option allows for film control at panel temperatures of up to 300 degrees Celsius.

Featuring fast and repeatable Copper-to-Gallium ratio determination with both cross-web and cross-panel gradient analysis capability, SMX-ILH enables PV panel manufacturers to realize significant yield improvements and conversion efficiency gains in production.

Solar Metrology's **SMX Measurement System** provides a production-ready suite of thin film thickness and composition measurement tools for research and process development, in-process monitoring and post-process quality control.

Solar Metrology is a global leader in the development and manufacture of high-performance X-Ray Fluorescence (XRF) analysis tools, specifically engineered to meet the demanding thin film measurement requirements of the solar electric and renewable power industries.

For additional information about Solar Metrology, contact info@solarmetrology.com or visit www.solarmetrology.com.

